JSRAM: A Circuit-Level Technique for Trading-Off Robustness and Capacity in Cache Memories

URL: http://ieeexplore.ieee.org/xpl/articleDetails.jsp?reload=true&arnumber=7309554

Authors: Ahangari, Hamzeh / Yalcin, Gulay / Ozturk, Ozcan / Unsal, Osman / Cristal, Adrián

Publication: 2015 IEEE Computer Society Annual Symposium on VLSI

Place Published: Montpellier, France

Pagination: 149-154

Barcelona Supercomputing Center - Centro Nacional de Supercomputación